



21st IEEE European Test Symposium

Mövenpick Hotel Amsterdam City Centre

Amsterdam, the Netherlands

May 23 – 27, 2016

www.ets16.nl



General Chair

Said Hamdioui (NL)

General Vice Chairs

Maria K. Michael (CY)
Bram Kruseman (NL)

Program Chair

Giorgio Di Natale (FR)

Program Vice Chair

Haralampos Stratigopoulos (FR)

Topic Chairs

Rolf Drechsler (DE)
Régis Leveugle (FR)
Teresa McLaurin (US)
Ilia Polian (DE)
Ozgur Sinanoglu (AE)
Mehdi Tahoori (DE)
Jerzy Tyszer (PL)
Xiaoqing Wen (JP)
Luigi Carro (BR)
Krish Chakrabarty (US)
Gildas Leger (ES)

ETS² Co-Chairs

Rene Segers (NL)
Matteo Sonza Reorda (IT)

Panel Chair

Patrick Girard (FR)
Ioana Vatajelu (IT)

Embedded Tutorial Chairs

Zebo Peng (SE)
Paolo Bernardi (IT)

Special Session Chairs

Sybille Hellebrand (DE)
Saqib Khursheed (UK)

Industrial Relations Chairs

Erik Jan Marinissen (BE)
Hans Manhaeve (BE)

Publication Chairs

Alberto Bosio (FR)
Stephan Eggersgluess (DE)

Web chair

Mottaqiallah Taouil (NL)

Publicity Chairs

Maksim Jenihhin (EE)
Qiang Xu (HK)
Ioannis Voyiatzis (GR)

Award Chairs

Bernd Becker (DE)
Adit Singh (US)

ETS Fringe Workshops

Lorena Anghel (FR)
Michel Renovell (FR)

Regional Liaisons

Baker Mohammad (UAE)
Riccardo Reis (BR)
Nicola Nicolici (CA)
Serge Demidenko (NZ)
Ashraf Farghaly Salem (EG)
Shi-Yu Huang (TW)

TSS (Test Spring School) Chairs

Paolo Prinetto (IT)
Lorena Anghel (FR)

Steering Committee

Paolo Prinetto (IT) – Chair
Lorena Anghel (FR), Bernd Becker (DE),
Joan Figueras (ES), Patrick Girard (FR),
Pete Harrod (UK), Sybille Hellebrand (DE),
Hans Manhaeve (BE), Maria K. Michael (CY),
Said Hamdioui (NL), Erik Jan Marinissen (BE),
Liviu Miclea (RO), Zebo Peng (SE),
Michel Renovell (FR), Jochen Rivoir (DE),
Matteo Sonza Reorda (IT), Hans-Joachim Wunderlich (DE),
Yervant Zorian (US)

Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics and new trends in the area of electronic-based circuit and system testing. In 2016, ETS will take place in Amsterdam, The Netherlands. It is organized by the Delft University of Technology, which co-sponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). ETS also features a special track on Emerging Test Strategies (ETS²), where new problems and ideas can be discussed in an informal atmosphere. ETS is the major event of the European Test Week that includes TSS (Test Spring School) and fringe workshops.

You are invited to participate and submit your contributions to ETS'16. The areas of interest include (but are not limited to) the following topics:

- Analog Test
- ATE Hardware and Software
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self-Test (BIST)
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test (DfT)
- Design for Manufacturing (DfM)
- Diagnosis and Silicon Debug
- Economics of Test
- Emerging Technologies
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- GPU Test
- High-Speed I/O Test
- Low-Power IC Test
- Memory Test and Repair
- MEMS Test
- Microprocessor Test
- Mixed-Signal Test
- Multi-/Many-core Processor Test
- Nanotechnology Test
- On-line Test
- Power Issues in Test
- Reconfigurable System Test
- Reliability
- RF Test
- Security and Trust Issues in Test
- Self-Repair
- Sensor Test
- Signal Integrity Test
- SiP, Stacked, 3D IC Test
- SoC Test
- Soft Errors
- Standards in Test
- System Test
- Test Compression
- Test Quality
- Test Synthesis
- Thermal Issues in Test
- Validation and Verification
- Variability Issues in Test
- Yield Analysis and Enhancement

Publication – ETS'16 will produce electronic formal proceedings - with ISBN number, and to be indexed in the IEEE Xplore digital library and other bibliographical search engines.

Submissions – ETS'16 seeks original, unpublished contributions of the following types:

- **Scientific papers** for the Formal Proceedings, presenting novel and complete research work
 - **Special sessions, Panels, and embedded tutorials**
 - **Contributions for the special track** on Emerging Test Strategies (ETS²)
- ETS'16 also seeks proposals for:
- **Vendor and Table-Top Demos presentations** focusing on new features of test related products
 - **Fringe workshops**, to be held on May 26 and 27
 - **Fringe meetings**, to be held during the European Test Week

Key Dates:

- Submission of title, abstract, authors: **December 7, 2015**
- **Full submission:** **December 14, 2015**
- Notification of acceptance: **February 12, 2016**
- Camera-ready manuscript: **March 13, 2016**

Further Information:

Said Hamdioui – General Chair
Delft University of Technology
Mekelweg 4, 2628 CD, Delft
The Netherlands
Tel: +31-(0)15 278 3643
E-Mail: S.Hamdioui@tudelft.nl

Giorgio Di Natale – Program Chair
LIRMM – CNRS/University of Montpellier
161 rue Ada, 34095 Montpellier
France
Tel: +33 467 41 85 01
E-Mail: giorgio.dinatale@lirmm.fr

